

LASER BASED SAMPLE PREPARATION FOR ADVANCED PACKAGING APPLICATIONS



Thomas Höche
Michael Krause

Fraunhofer IMWS Halle

Fraunhofer Center for Applied Microstructure Diagnostics CAM

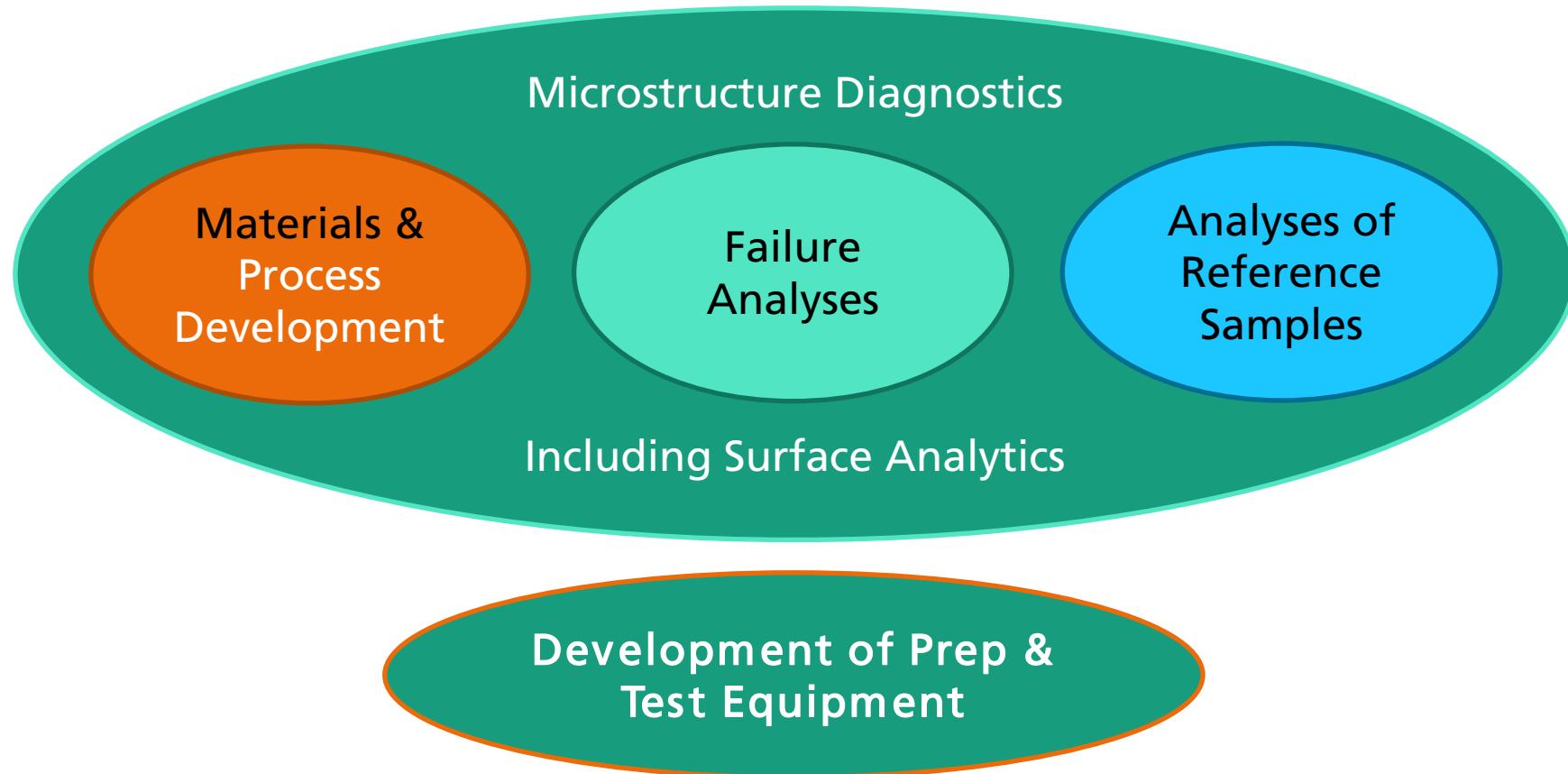
Microstructure. Properties. Relationship.



- 25 years experience in microstructure diagnostics.
- Comprehensive base of equipment:
 - Non-destructive testing
 - Reliable target prep
 - State-of-the-art nano analytics
- Continuous development of preparation and analytical methods.

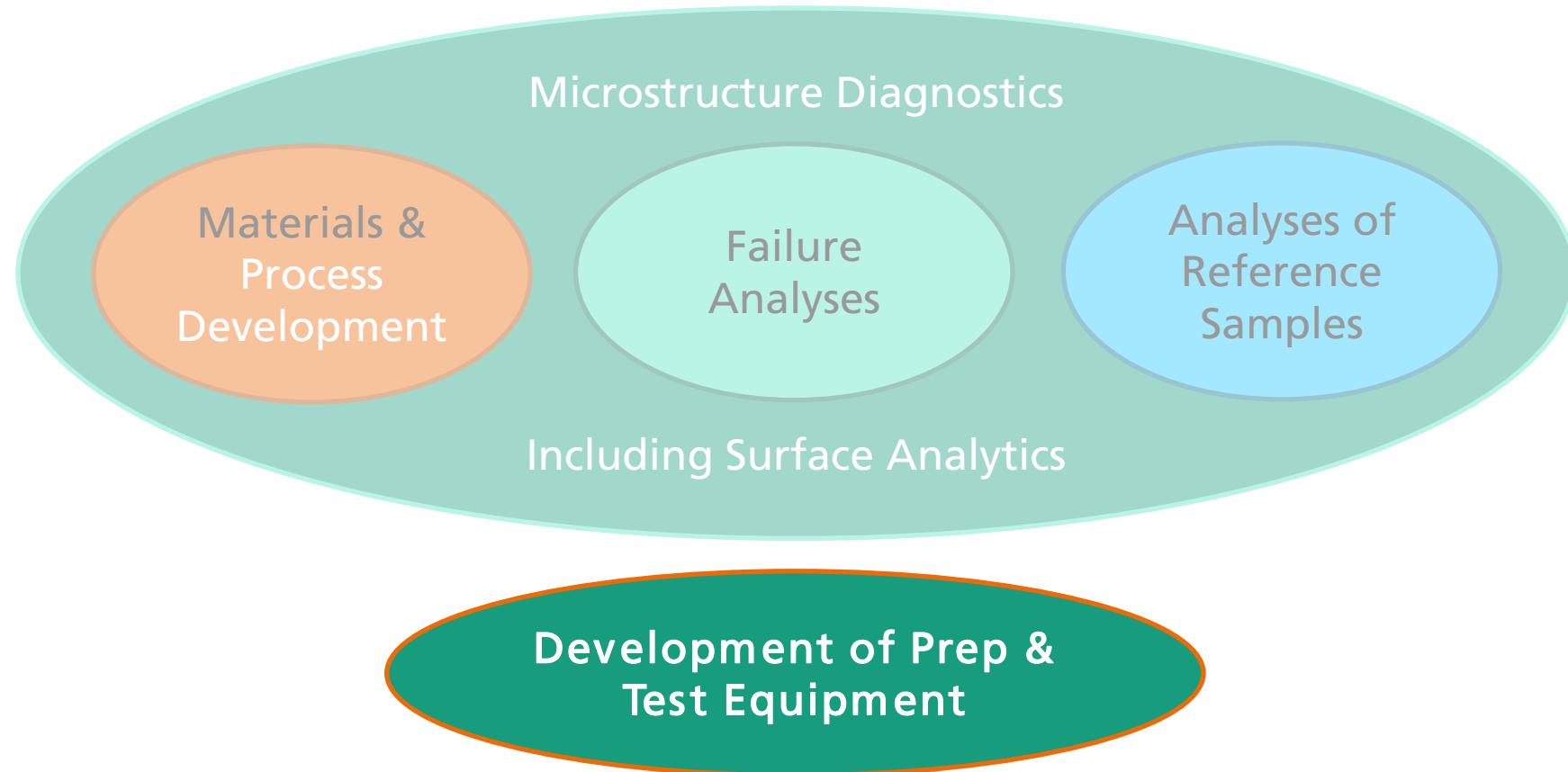
Fraunhofer Center for Applied Microstructure Diagnostics CAM

Services Offered



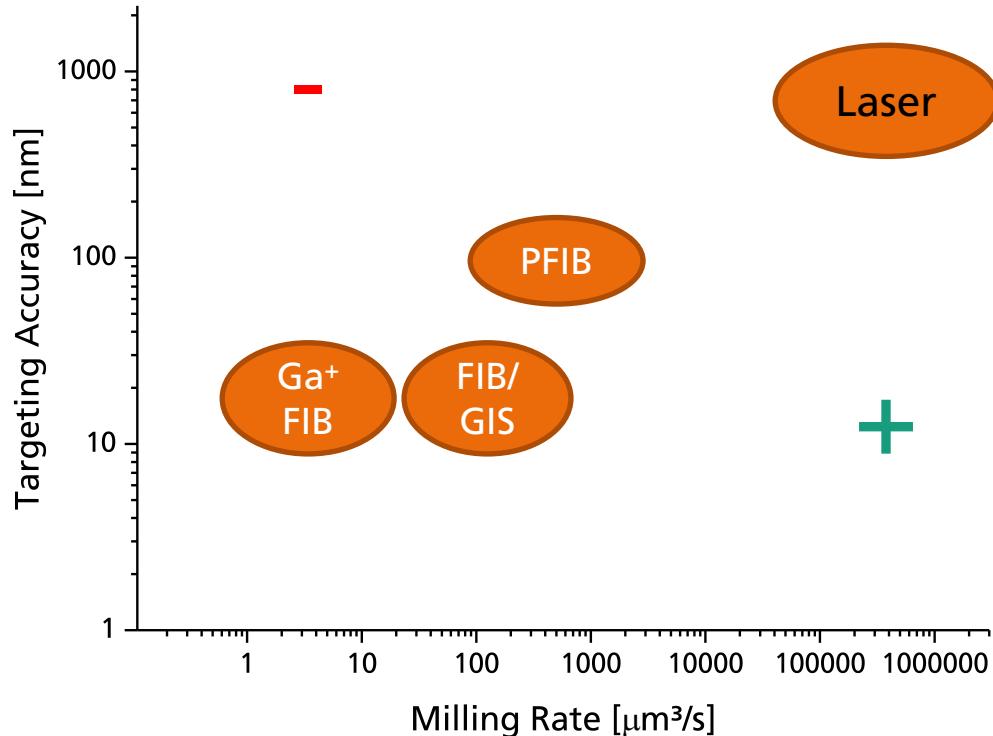
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Services Offered

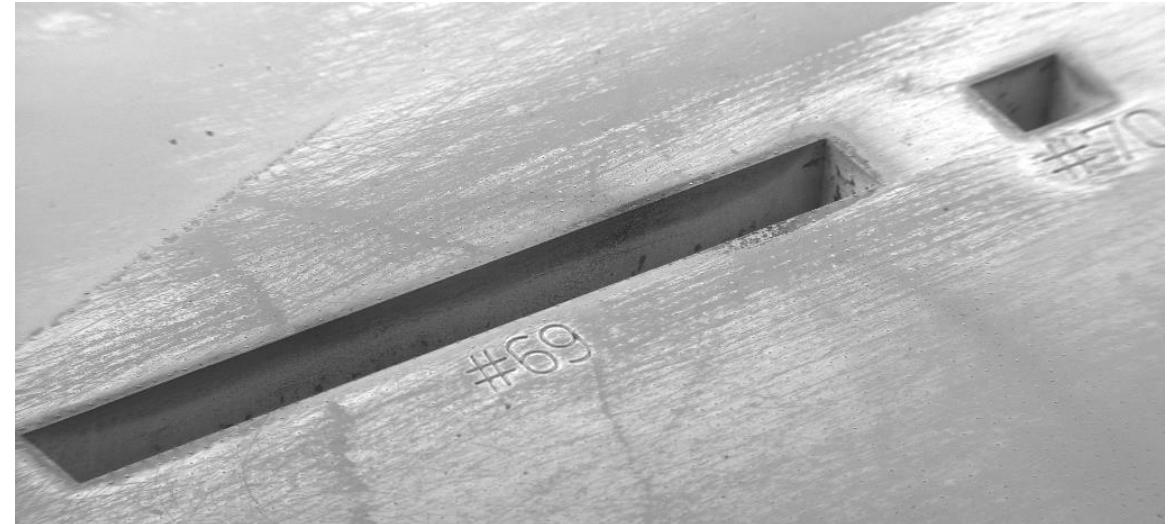


microPREP™

The Advantage of Being MUCH Faster



In Parts after: Martens *et al.*, EuroSimE, 2010.

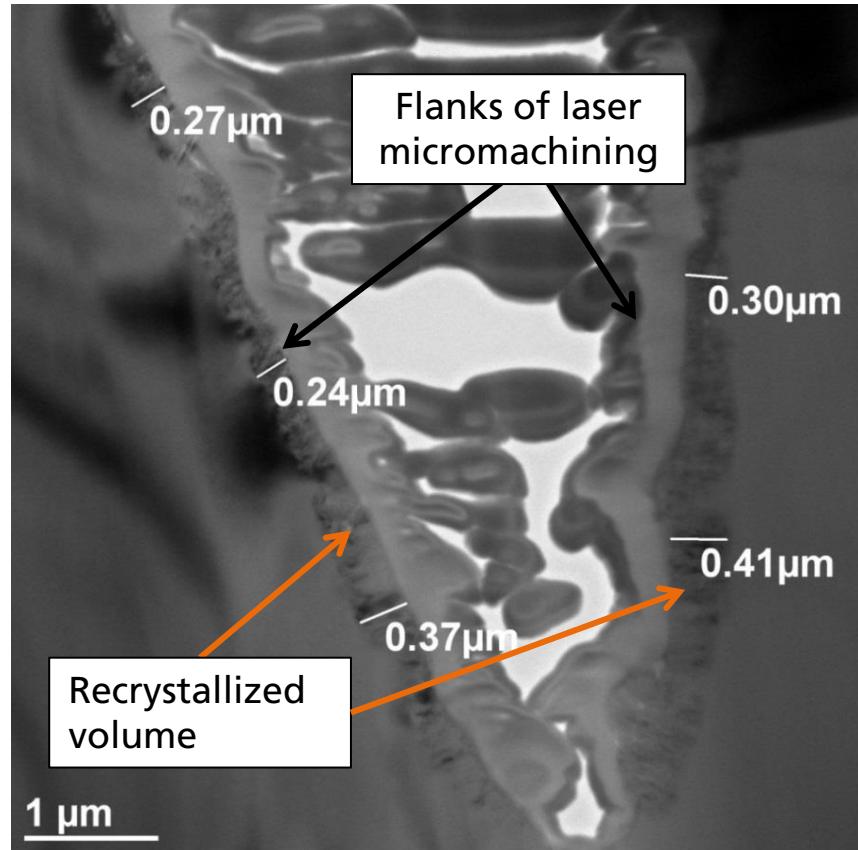


#	Size of cut	Time required	
		microPREP™	FIB
69	3.000 x 300 x 300 μm^3	23 min 40 s	~6 months*
70	300 x 300 x 250 μm^3	3 min 40 s	17.5 days*

*Not practical for a FIB system

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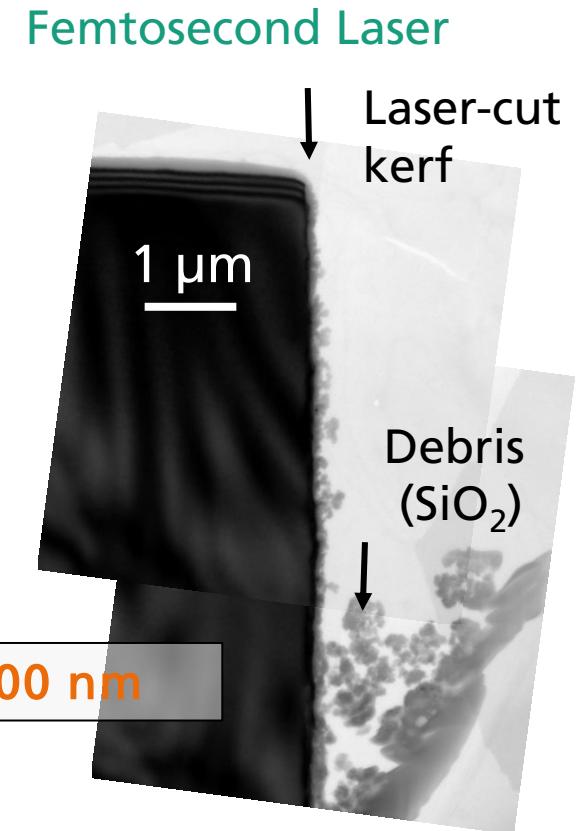
Price to Be Paid for Being MUCH Faster?



Pico-second
Laser

Laser-affected zone
is omnipresent.

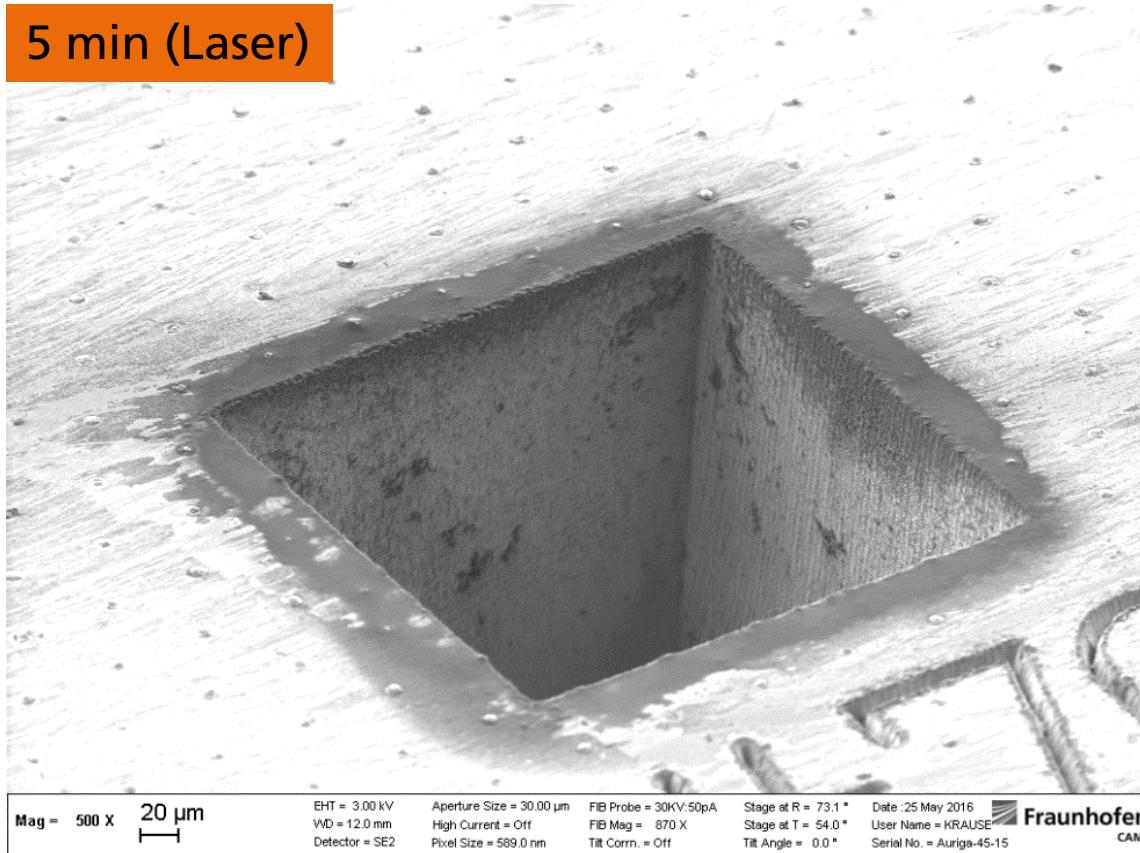
It needs to become
removed with ion-
beam polishing.



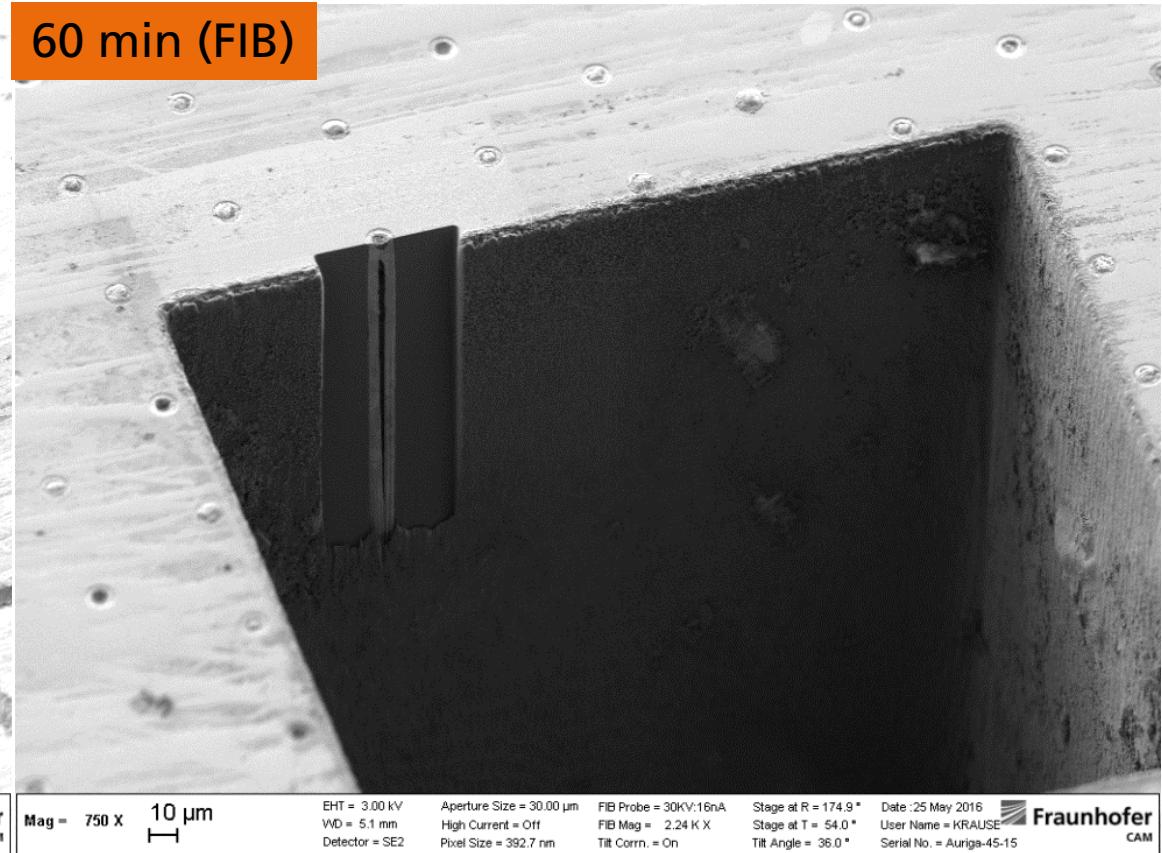
microPREPTM

Advanced Packaging, Surgical (Excavation)

5 min (Laser)

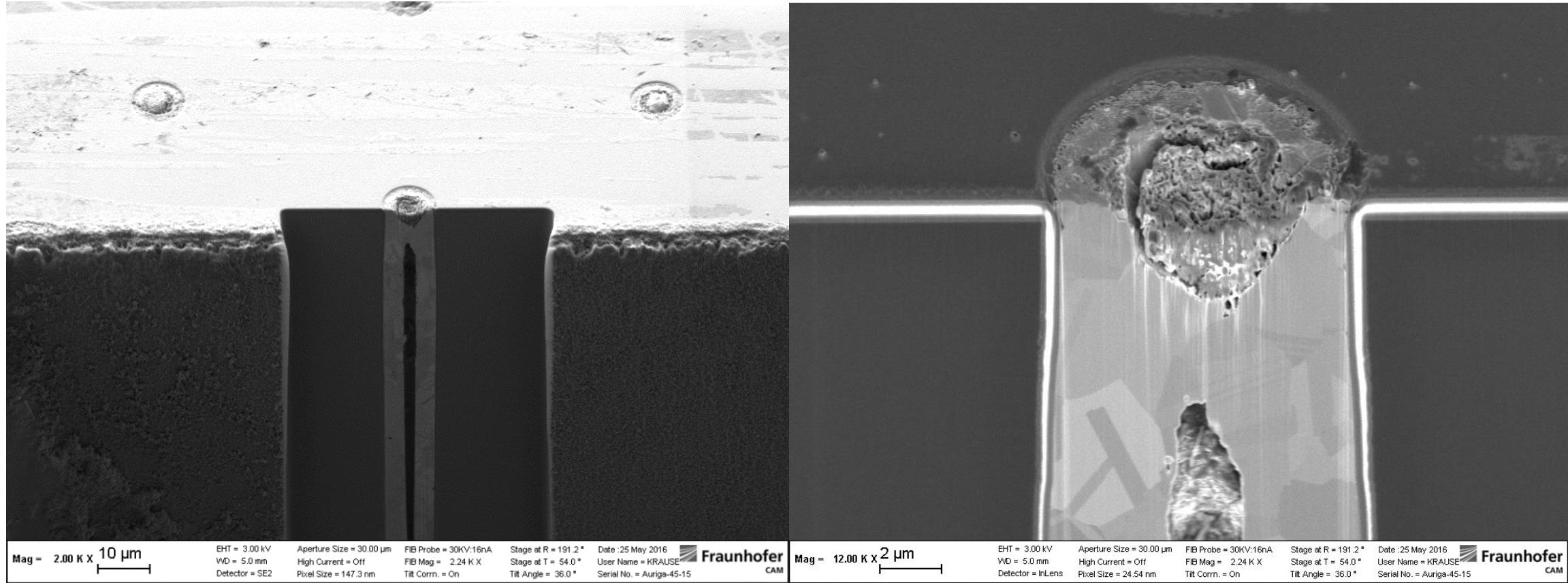


60 min (FIB)



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Advanced Packaging, Surgical (Excavation)

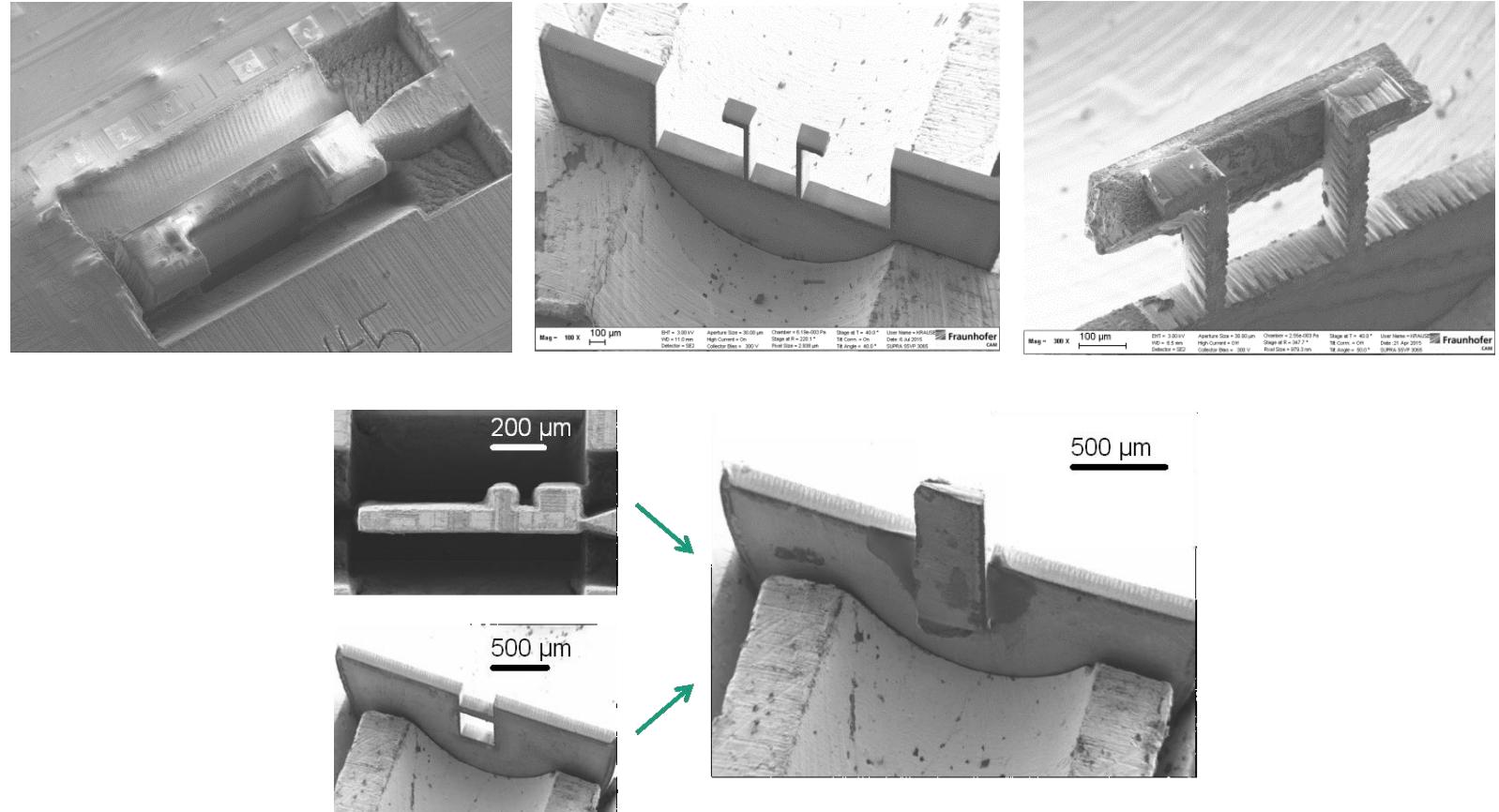


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Advanced Packaging, Surgical (Excavation)

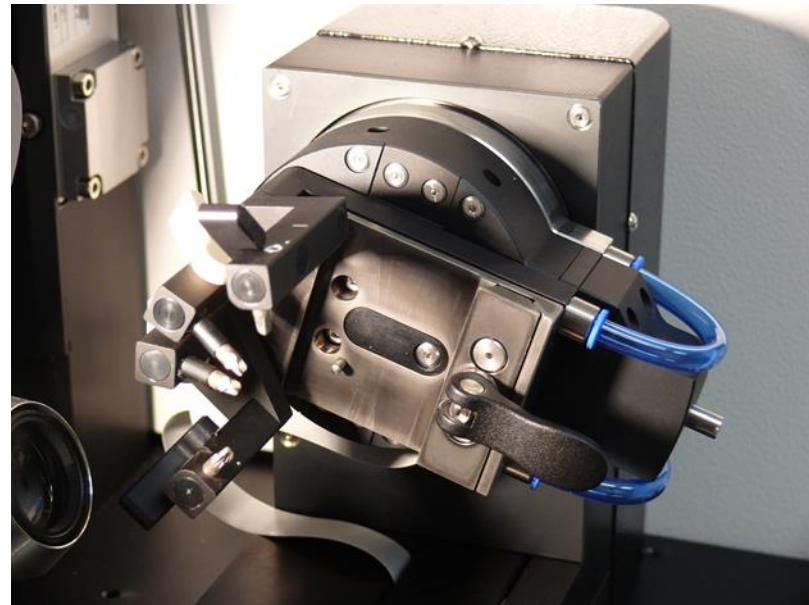


■ XL Chunk™ holder



microPREPTM

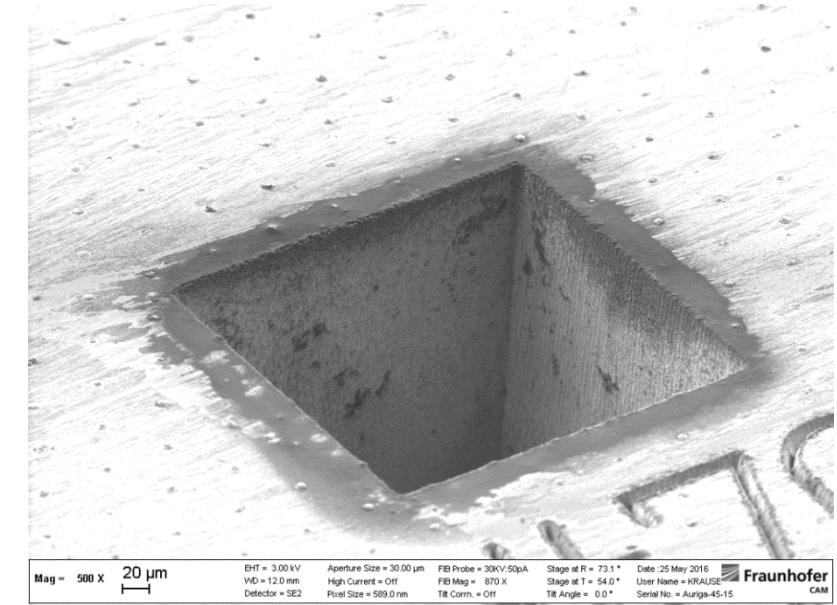
Advanced Packaging, Surgical (Excavation)



tilting

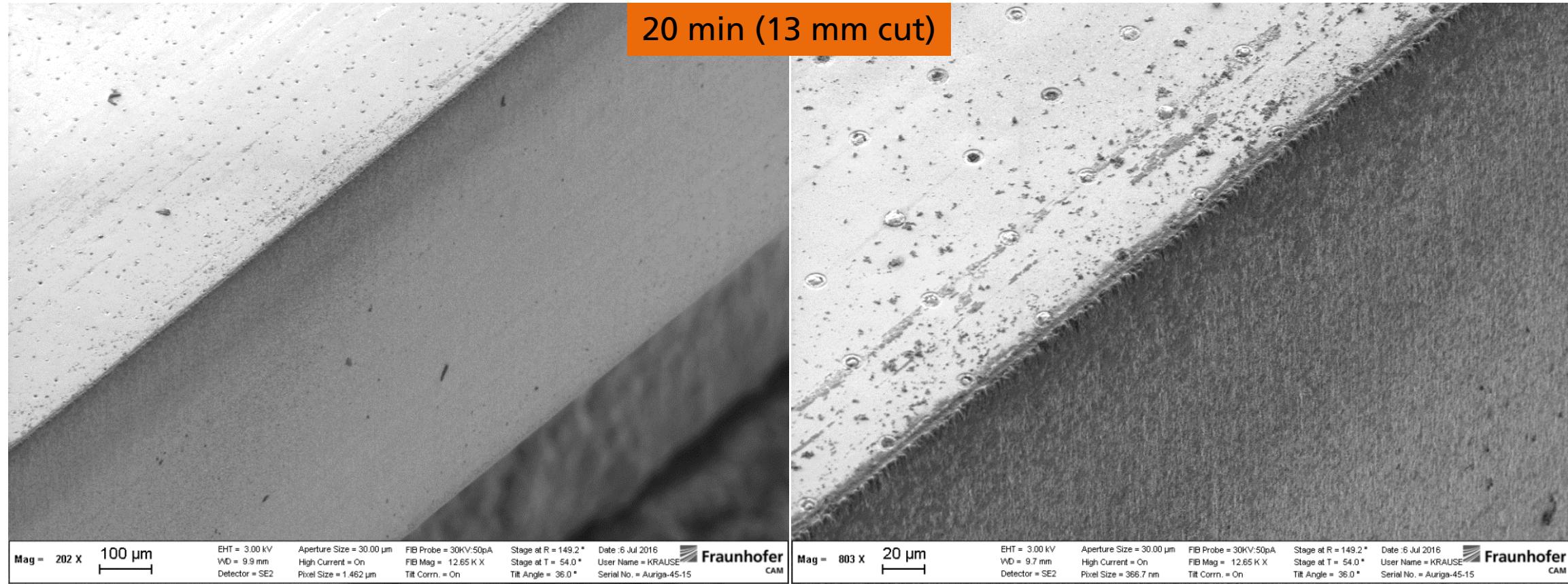


rotating



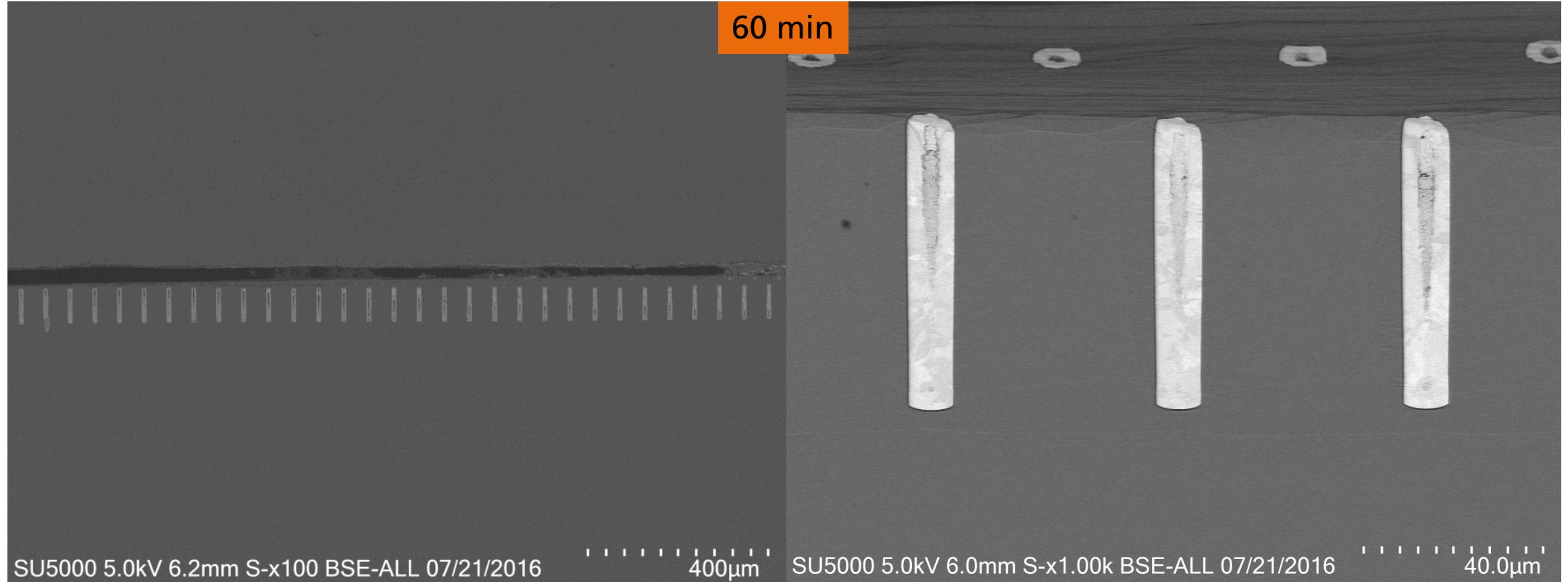
microPREP™

Advanced Packaging, High-Throughput (Cutting)



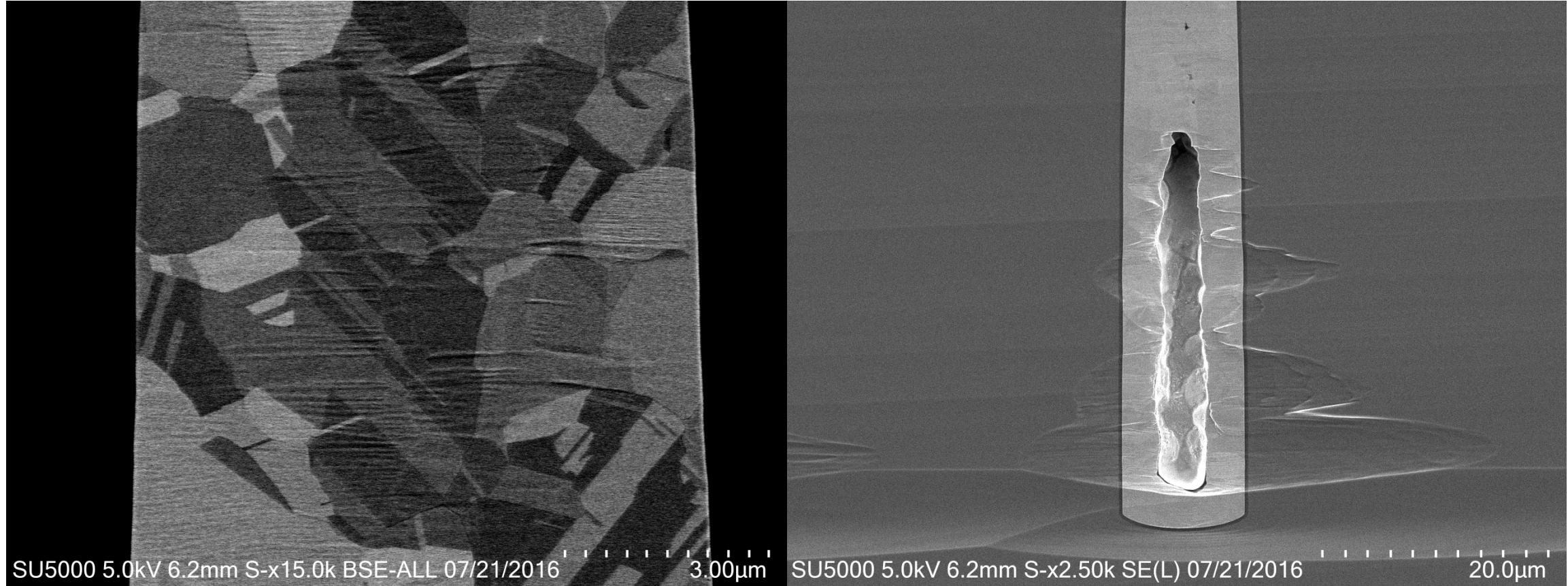
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Advanced Packaging, High-Throughput (Cutting)



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Advanced Packaging, High-Throughput (Cutting)



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Advanced Packaging - Conclusions

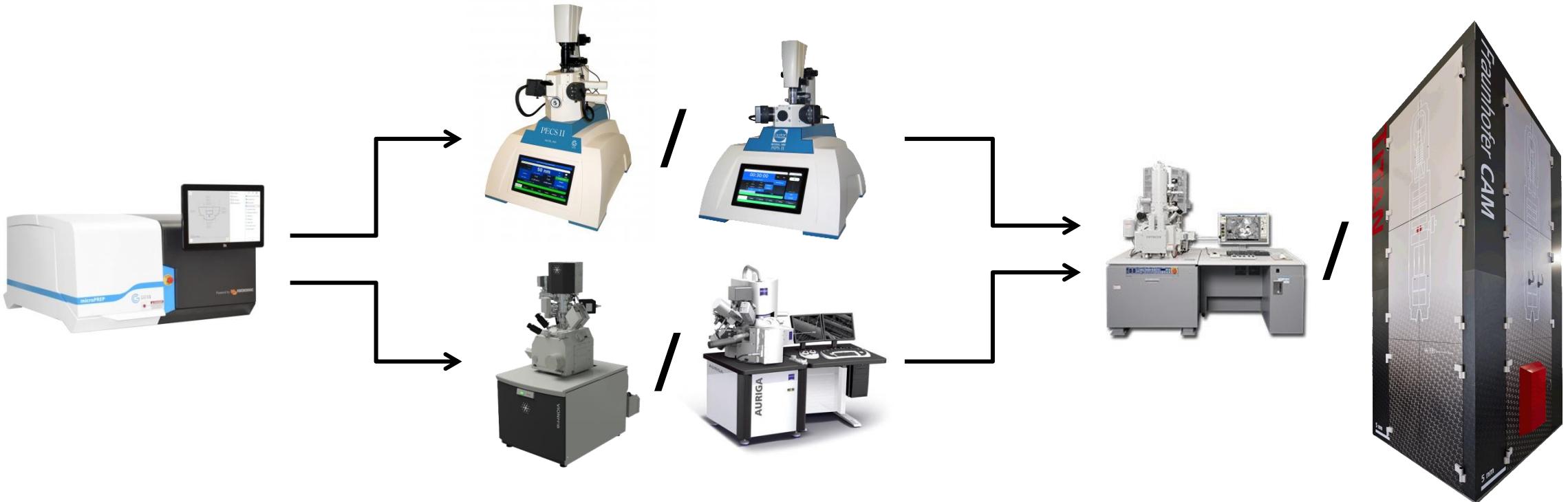
- microPREP™ to speed up preparation by orders of magnitude.
- Applicable to all (including at-the-wavelength-of-laser transparent) materials.
- Laser-affected zone precisely controlled.
- Positioning of the laser to less than within 2-3 µm.
- Minimal cross-contamination of ion-beam-erosion tools.

- Harmonized workflows with PECS to facilitate prep for advanced packaging.



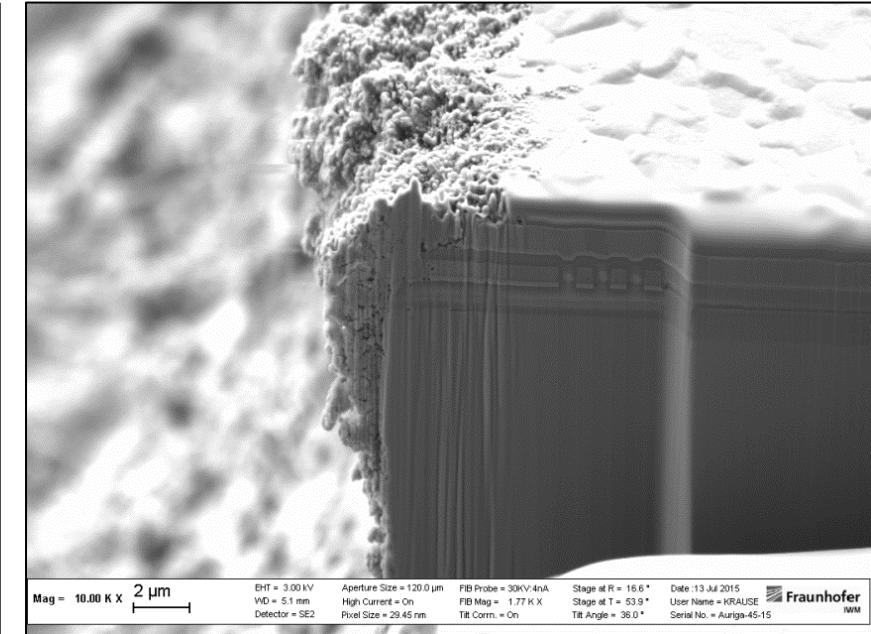
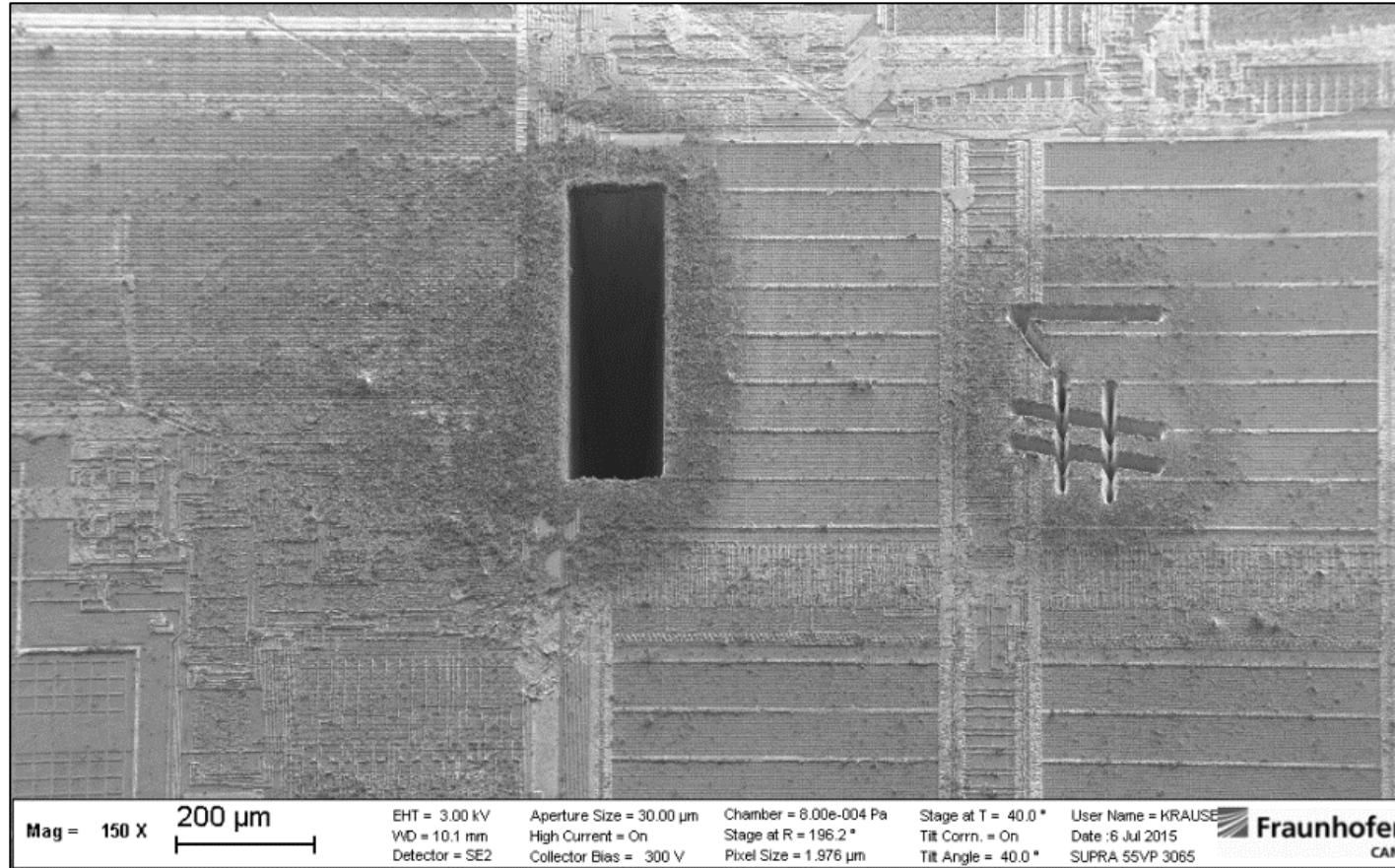
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A Versatile Plattform



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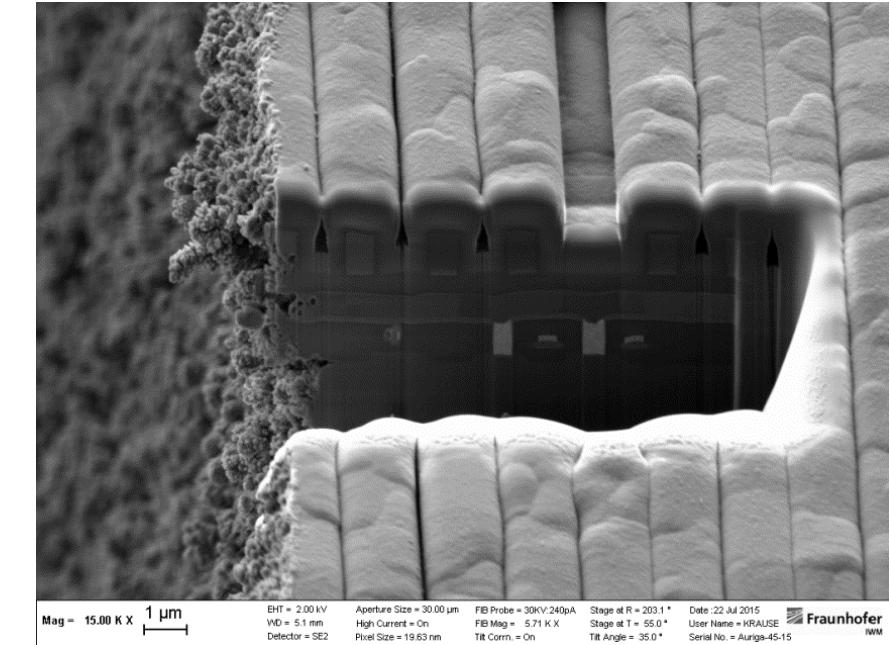
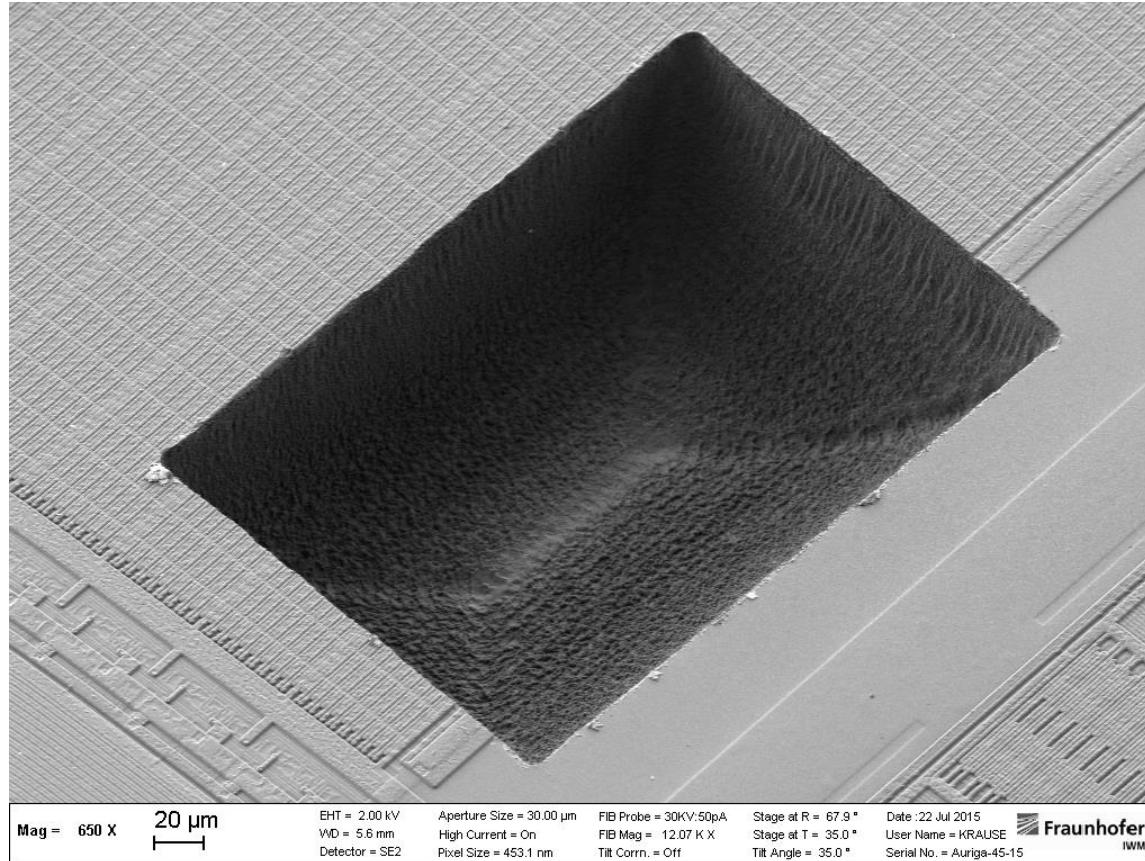
Standard Cleanliness/Damage



- Debris, courtinging
- Rounded flank entrance
- Thermal load to edge

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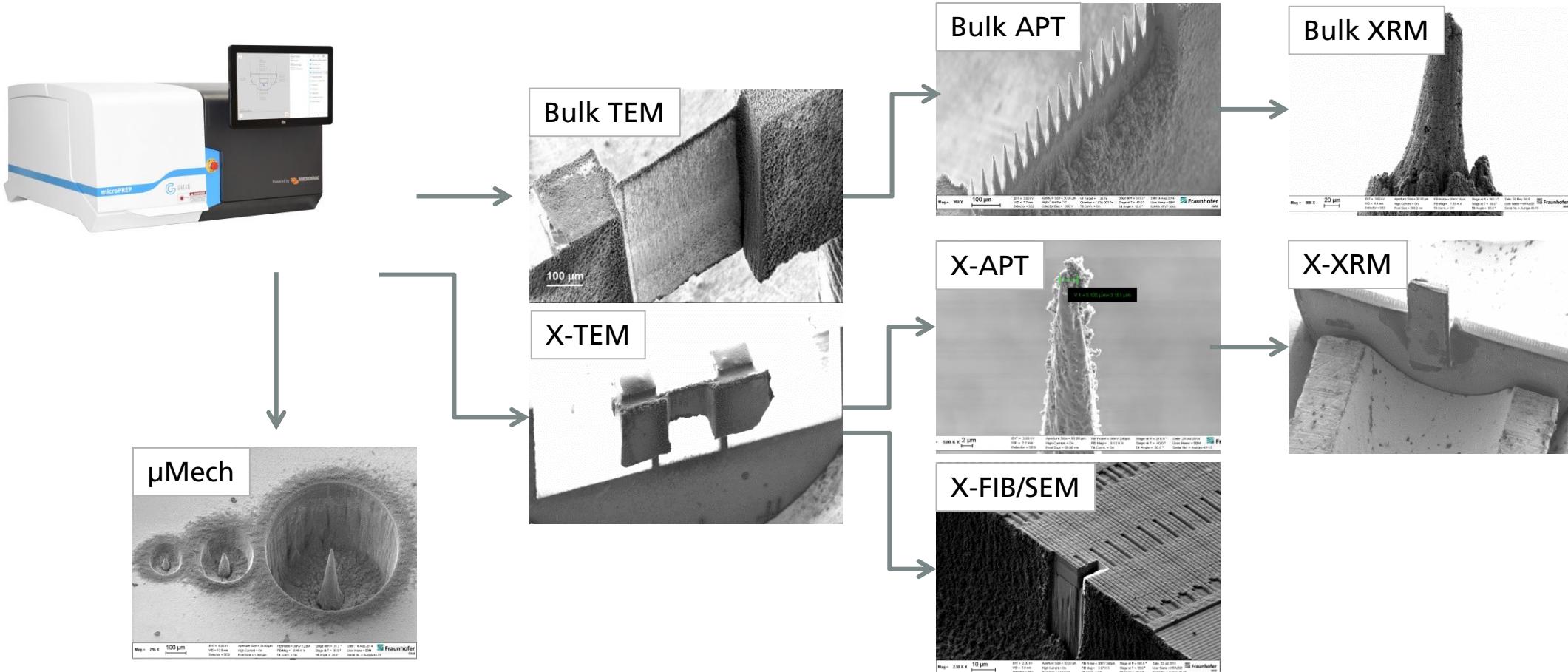
Advanced Cleanliness & Reduced Damage



- No burr, sharp flanks
- Applicable to all materials
- No debris

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A Versatile Platform Serving Manifold Workflows



microPREP™

Come Closer and Have a Look!

